Budapest University of Technology and Economics

Department of Measurement and Information Systems

Model-Based Automatic Test Generation for EventDriven Embedded Systems Using Model Checkers

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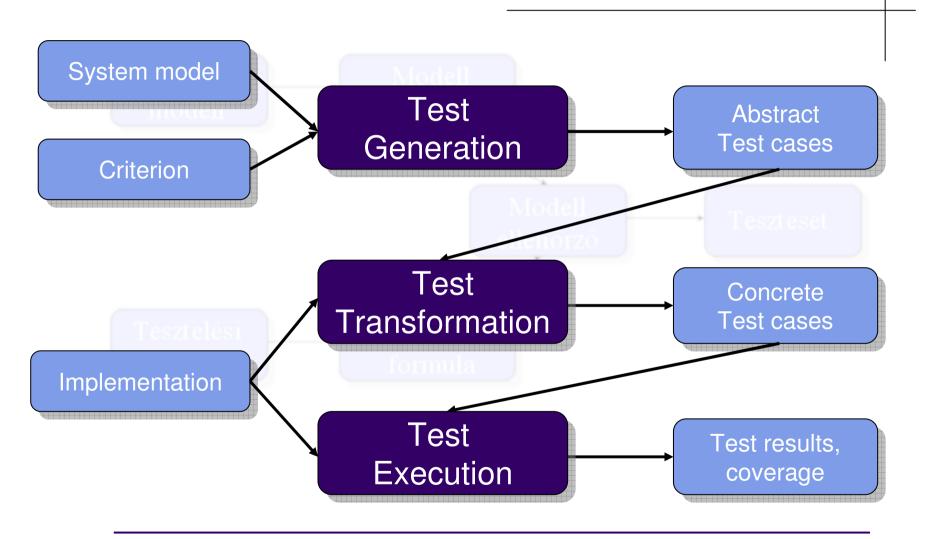
Testing concepts

- Goal: improving the quality of the system
- Test case: input events and expected output actions representing a typical paths
- Test suite: set of test cases
- Test requirement: a specific sub goal for testing, e.g. call a function
- Coverage criterion: determines a set of test requirements, e.g. cover all statements

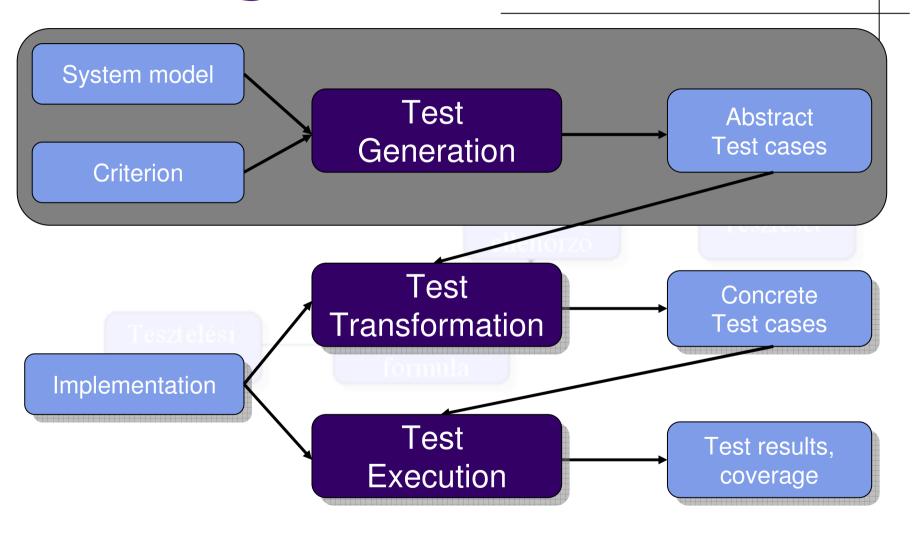
Problems in testing

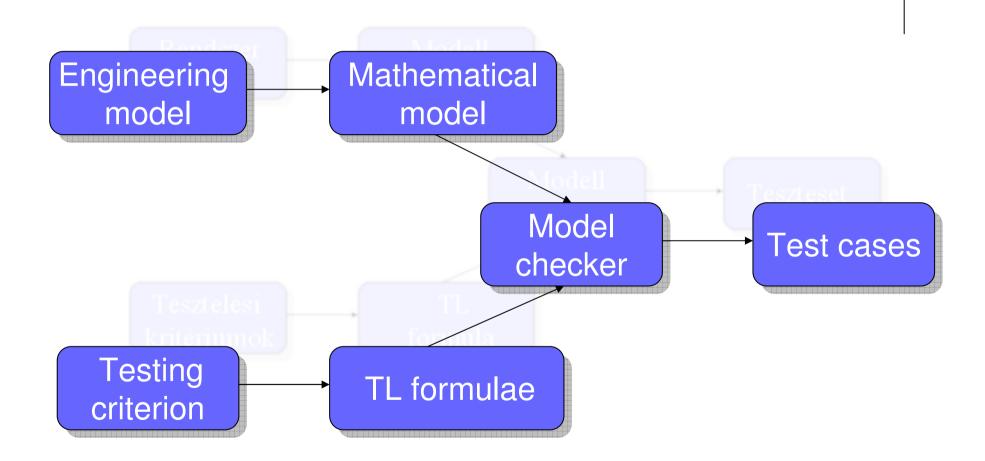
- Test cases are written manually
 - Time and resource consuming
- If the specification/code changes all the test cases should be modified
- Detailed behavioural model can help
 - Parts of the testing tasks can be automated

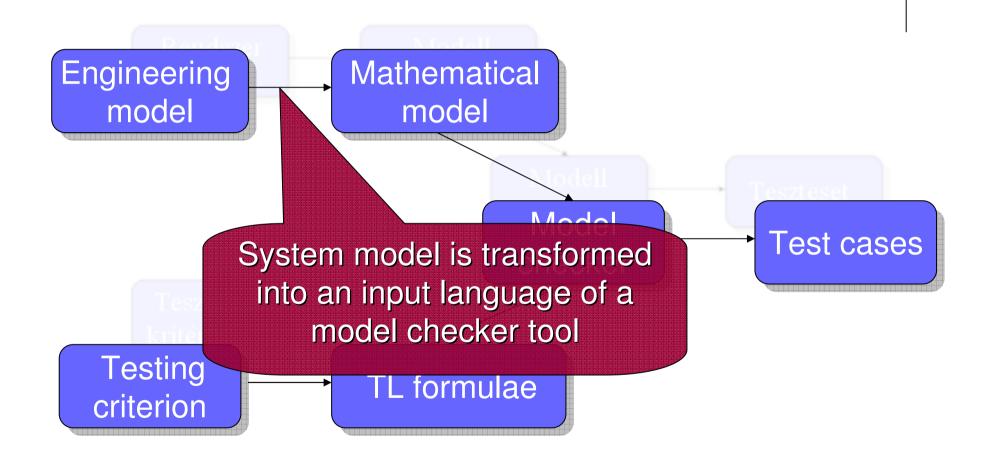
Testing framework

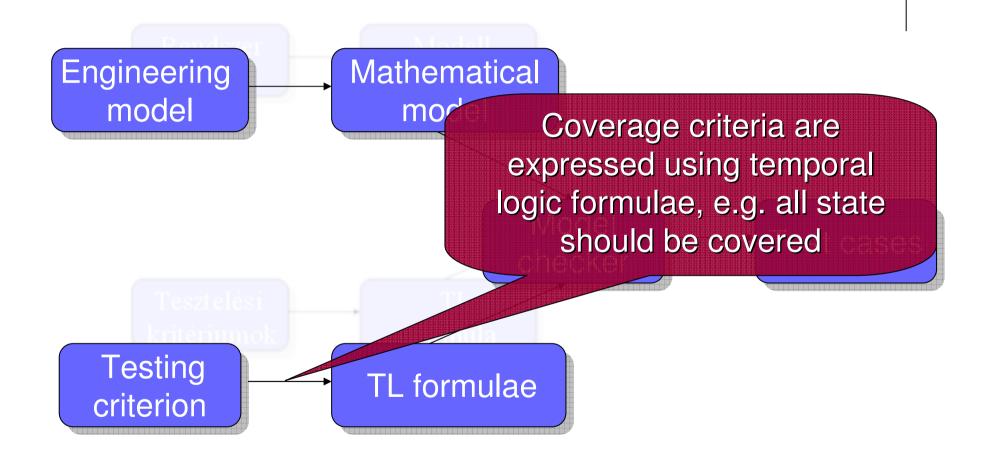


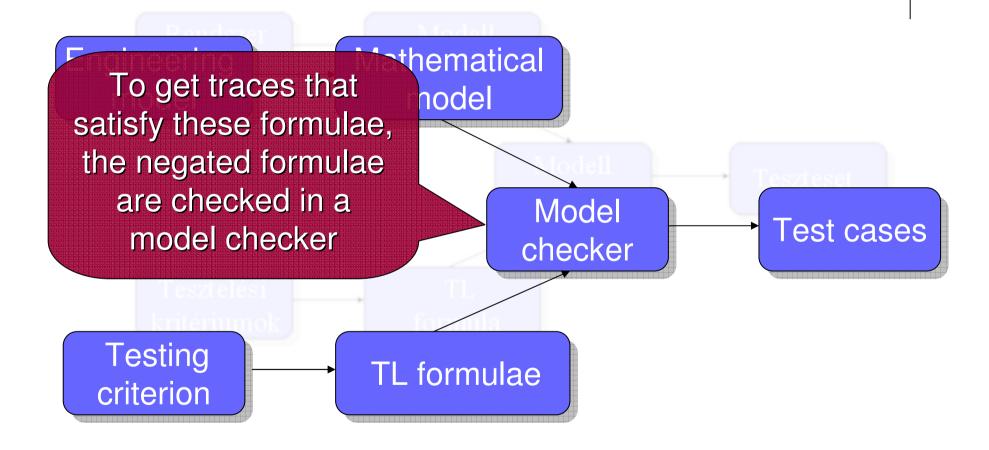
Testing framework

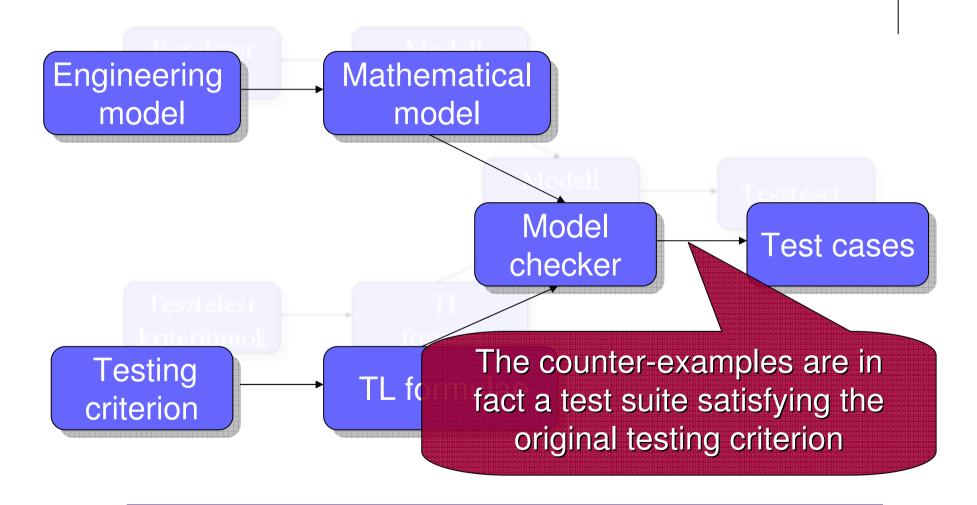




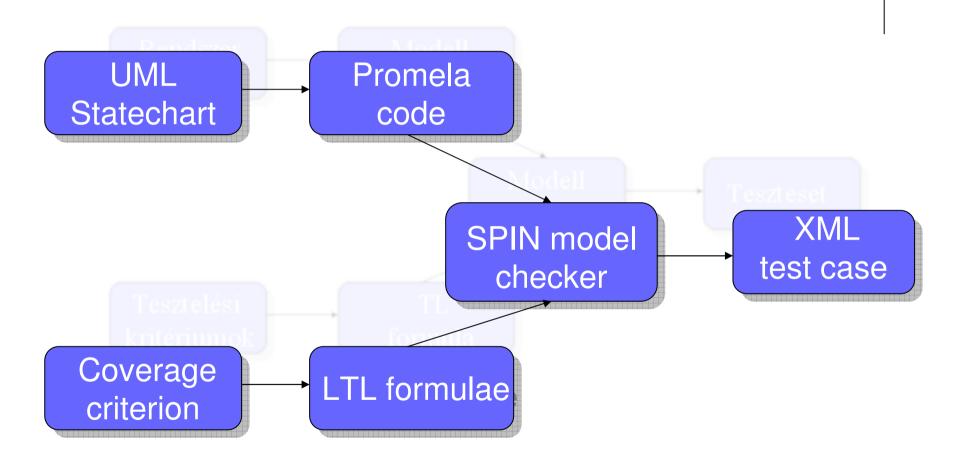








Implemented test generator



Implementation details

- Model transformation
 - UML → Extended Hierarchical Automata → Promela
- Test generation input
 - Model: UML Statechart representing the behaviour
 - Criterion: coverage criterion on the model
 - Currently: All or selected states/transition covered, custom temporal logic formulae
- Output
 - Events collected from the SPIN detailed trace

Efficiency of test generation

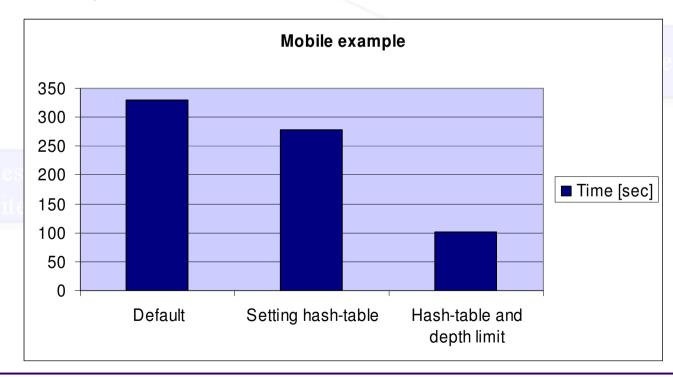
- Classical model checking: exhaustive verification of the full state space
- Test generation: finding a minimal length counter-example quickly
 - → special configuration is necessary.
- Measurements:
 - Effects of SPIN's 10 parameters on runtime
 - Goal: minimize time needed for test generation while test suite is minimal in length

Analyzed SPIN parameters

- -dBFS: Breadth First Search
- -m: depth limit in Depth First Search
- -i and –I: minimal counter-example iteratively
- -w: size of the hash table to store states
- Other parameters (e.g. –dNOFAIR,
 -dSAFETY) did not have significant effect

Experiment 1: Mobile model

- Statechart describing behaviour of a mobile phone
- 10 states, 21 transitions



Detailed results

	Options	Duration	Sum length	Shortest test
	-i	22m 32.46s	17	3
-	-dBFS	11m 48.83s	Modell 17	3
	-i -m1000	4m 47.23s	ellenőrző 17	3
	-1	2m 48.78s	25	6
Te kri	default	2m 04.86s	385	94
	-I -m1000	1m 46.64s	22	4
	-m1000	1m 25.48s	97	16
	-m200 -w24	46.7s	17	3

Detailed result

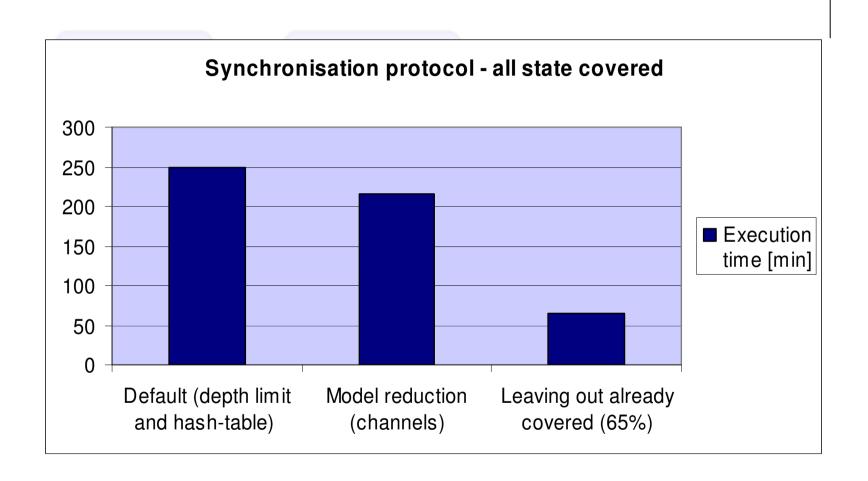
Iterative search: short test cases but long duration

Options	Duration	BFS: good results, but ran out of memory in more complex models	
i	22m 32.46s		
-dBFS	11m 48.83s	17 3	
-i -m1000	4m 47.23s	Limiting the depth resulted	
<u>-l</u>	2m 48.78s	always in shorter execution	
default	2m 04.86s	385 94	
-I -m1000	1m 46 045	Limiting the depth and	
-m1000	1m 25.48s		
-m200 -w24	46./s	the optimal setting	

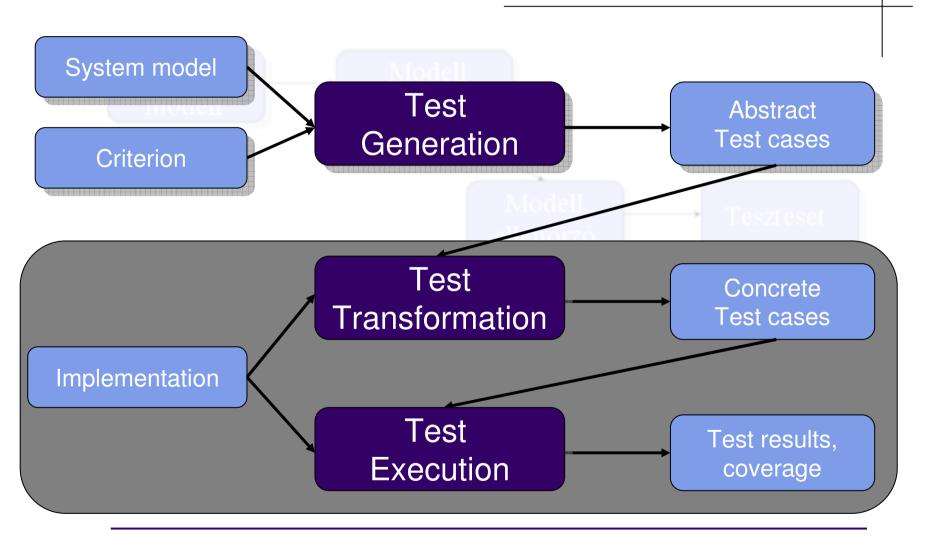
Real-life case study

- Industrial partner's synchronization protocol
- 5 objects, 31 states, 174 transitions
- 2e+08 states visited
- Further techniques needed:
 - State space compression bit-state hashing
 - Reduction of the model in a conservative manner
 - Leaving out requirements already covered
- Finding minimal length/size test suite is NP-complete

Synchronisation protocol - results



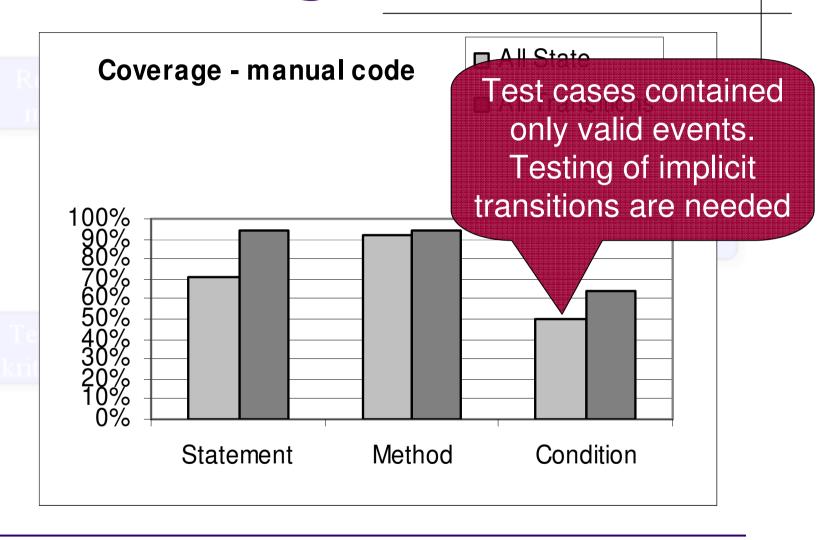
Testing framework



Testing implementations

- Use the abstract test cases to test conformance of an implementation
- Definition of a test interface (mapping)
- Conducted experiments
 - Mobile model, with two implementation:
 - manually coded using nested switch method
 - Statechart Java code generator
 - Two test execution framework:
 - JUnit, Rational Robot

Code coverage results



Conclusion

- Tool chain for automatic test generation of event-driven systems
- Multiple coverage criteria on the model
- Optimizing model checker for test generation
- Applying tests to implementation
- Code coverage on implementation
- Real-time systems: generating also timing information